

<b>Notice of References Cited</b>	Application/Control No. 10/582,160		Applicant(s)/Patent Under Reexamination LEE, YOUNG SU	
	Examiner Joseph L. Perrin		Art Unit 1792	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,755,268 A	07-1988	Matsuo et al.	205/746
*	B	US-2004/0025263 A1	02-2004	Kim et al.	8/159
*	C	US-6,743,351 B1	06-2004	Arai et al.	205/701
*	D	US-2004/0172985 A1	09-2004	Mamiya et al.	068/012.05
*	E	US-2004/0205899 A1	10-2004	Park et al.	008/159
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	<del>WO 2001000 A1</del>	10-2002	World Intellect	MAMIYA et al.	D06F 39/08
	O	WO 02081808				
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Translation of KR 2002-012368 A, date not applicable.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.